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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Vidya VENKATACHALAM

Group Art Unit: 2613

Application No.: 10/632,823

Examiner: Unknown

Filed: August 4, 2003

Docket No.: 115975

For: METHODS AND APPARATUS FOR INSPECTION OF LINES EMBEDDED IN HIGHLY TEXTURED MATERIAL

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. The references were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully submitted,

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Date: January 4, 2006

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<p>DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p>

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 115975		APPLICATION NO. 10/632,823	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Vidya VENKATACHALAM			
				FILING DATE August 4, 2003		GROUP 2613	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	1	Lambert et al., "Thickness Measurement of Food Packing Films," <i>5th International Conference on Quality Control By Artificial Vision</i> , pp. 287-291, May 1999.					
	2	Doudkin et al., "Contour Extraction Algorithms for LSI Circuit Video Image Processing," <i>Proceedings of the International Workshop on Intelligent Data Acquisition and Advanced Computing Systems: Technology and Applications</i> , pp. 69-72, July 2001.					
	3	Allada et al., "Efficient Vertex Detection Algorithms Using the Hough Transform," <i>International Journal of Advanced Manufacturing Technology</i> , Vol. 11, No. 6, pp. 394-405, 1996.					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: January 4, 2006